	APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Page 1										
E	SCC	Component Title:	Capacito 101M, 2	ors, Microwa 201M, 400M	ave, Silico and 401M	n, MC /I)S, Nal	ked Die based on Types		Appl. No	Э.
		Executive Member	r: CNES	\$			D	ate: 26/01/2021		286F	
Components (includir	ng series and families	s) submitted for Exte	nsion of Qu	alification <i>F</i>	Approval:						1
ESCC COMPONENT NO.	VARIANTS	RANGE OF	RANGE OF COMPONENTS BASED ON					TEST VEHICLE / S		COMPONENT SIMILAR	Г
5711/002	01 to 31	40V to 200 V	40V to 200 V 400M					400M107A39M	All c	other variants	
Component Mr	anufacturar		of Monufac	turing Plant((~)	3	<u> </u>				
Cobham Microwave		31, avenue de	la Baltique	lunny riang	S)	3	Date	of original qualification ap	oprova	l:	4
		91978 Villebon France	-sur-Yvette	Cedex			Date:	: 15/12/2008			
							Certit	ficate Ref No. 286			
							Oortin	icale ner no. 200			
	L	5				6	7				7
ESCC Specifications Maintenance of qualif	used for fication testing:	Deviations to L used:	.VI testing a	and Detail 5	pecificatio	on	reference and date:				
Generic: 5010	Issue: 3	No 🖂 Y	No \boxtimes Yes \square (supply details in Box				2020	0614362-223 dated 02/06	3/2020		
Detail(s): 5711/002	2 Issue: 4	Deviation from	Deviation from current Specifications:								
		No 🖂 Y	No 🛛 Yes 🗌 (Supply details)								
Summary of procurer	nent or equivalent te	st results during curr	ent validity	period in su	pport of th	nis ap	plicatio	on (those to ESCC listed fi	irst)		0
Project Name	Testing Leve	el LAT	ſ		Date code			Quantity	Delive	red	
Various		Chart F4B		2018 - 202	20			>20 000			
PID changes since st	art of qualification		9 Cur	rrent PID V	erified by:	:		JL Roux, CNES			10
None 🗆							N	ame of Excutive Represe	ntative	3	
Minor* ⊠ Major* □	*Drovido dotoilo in h	0 //	Ret	NO: P	4D 302			Date:		18/04/2019	
Imajor Imajor<							10/04/2013				
							11				
Current Manufacturing facilities surveyed by: F.Martinez, ESA and JL Roux, CNES on 24/09/2014						14					
		((Name of E	xecutive Re	presentati	ive)			(Date)		
Satisfactory:	Yes 🛛	No 🗆	Explain								
Report Reference:	COBH-CIRC	-AUD-2014	-								

Component Uit: Capapetiers, Microwave, Silcon, MOS, Naked Die based on Types Appl. No. Zesculve Member: CNES Date: 2001/021 2867 Failure Analysis, DPA, NCCS available: Yes No (Supply date) Image: No. 2867 Failure Analysis, DPA, NCCS available: Yes No (Supply date) Image: No. 2867 Ref. No's and purposes: Image: No.	APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL							
Executive Member: CNES Date: 2807/2021 2807 Failure Analysis, DPA, NCCS available: Yes No (Supply data) Ref. No's and purposes:	ESCC	Component title:	Capacitors, M 101M, 201M,	icrowave, Silicon, M 400M and 401M	IOS, Naked D	ie based on Types	Appl. No.	
Pailure Analysis, DPA, NCCS available: Yes No (Supply data) Ref. No's and purposes: 13 The undersigned hereby cartifies on behalf of the ESCC Executive - that the above information is correct; - that the appropriate documentation has been required that the ongliance to all ESCC requirements is explained on the term of the component of the term of term of the term of ter		Executive Member:	CNES		Date:	26/01/2021	286F	
Ref. No's and purposes: 13 The tridersigned hereby certifies on behalf of the ESOC Exacultive . That the above information is correct. 13 The tridersigned hereby certifies on behalf of the ESOC Exacultive . That the above information is correct. 13 CNES as the responsible Executive Member for ESOC Qualification status to be extended to the component(s) listed herein. 14 Date: 24/02/2021 IP_BUSSENDI Continuation of Boxes above: 14 Box 9 : 14 Editorial changes : new edition of ESOC 5010 (issue 3) and Detailed Specification ESOC (issue 4), updated organisation chart. 14 Box 11 : The audit performed on Sept. 2014 focuseed on the manufacturer's isolator and directurer some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Failure Analysis, DPA, NCCS ava	ilable: Yes	🗆 No	⊠ (Supply da	ita)		12	
Is a undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct - that the appropriate documentation has been vealuated; - that thill compliance to all ESCC requirements is evidence (except as thate in the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsable Executive Member for ESCC qualification status to be extended to the component(s) listed heren. JP. BUSSENDT JP. BUSSENDT (Signature of the Executive Coordinator) Continuation of Boxes above: Ext 9: Editorial changes : new edition of ESCC 5010 (issue 3) and Detailed Specification ESCC (issue 4), updated organisation chart. Box 11: The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Ref. No's and purposes:							
Date: 24/02/2021	The undersigned hereby certifies on behalf that the appropriate documentation has bee (except as stated in box 15;) - that the repo CNES as the responsible Executive Membe	of the ESCC Executiv en evaluated; - that ful rts and data are availa er for ESCC qualificati	ve - that the abo I compliance to able at the ESC on status to be	ve information is con all ESCC requireme C Executive and the extended to the corr	rrect; - ents is eviden erefore applies nponent(s) lis	ce s on behalf of ted herein.	13	
Continuation of Boxes above: 14 Box 9 : Editorial changes : new edition of ESCC 5010 (Issue 3) and Detailed Specification ESCC (Issue 4), updated organisation chart. Box 11 : The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Date: 24/02/2021				(S	JP. BUSSENO	T Coordinator)	
Editorial changes : new edition of ESCC 5010 (Issue 3) and Detailed Specification ESCC (Issue 4), updated organisation chart. Box 11 : The audit performed on Sept. 2014 (ocussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Continuation of Boxes above: Box 9 :						14	
Box 11 : The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Editorial changes ; new edition of ESCC 50	10 (Issue 3) and Deta	iled Specificatio	n ESCC (Issue 4) u	updated orda	nisation chart		
The audit performed on Sept. 2014 focussed on the manufacturer's isolator and circulator products. However some areas (back end, screening) and general topics (quality, organisation,) are common with the sicilon components manufacturing and have benefited from it.	Box 11 :			(10000 F), C				

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		AP	PLICATION FOR EXTENSION OF ESCC QUA	ALIFICATION APPROVAL	Page 3
Q.S.C.	ESCC	Componen	t title: Capacitors, Microwave, Silicon, MOS 101M, 201M, 400M and 401M	S, Naked Die based on Types	Appl. No.
	1. S. 1	Executive N	Nember: CNES	Date: 26/01/2021	286F
Non comp	bliance to ESCC requirements:	•			15
No.:	Specification		Paragraph	Non compliance	
	oppontation				-
Additional	I tasks required to achieve full co	mpliance for	ESCC qualification or rationale for acceptability	of	10
noncompl	liance:				16
Executive	Manager Disposition				17
Applicatio	n Approval: Yes 🛛	No 🗆			
Action / R	emarks:				
				Digitall	y signed
				54 Q1 by Britt	a Schade
				Date: 2	021.03.30
Date:				10:51:2	6 +02'00'
				B. Schade: Head of the Produc and Safety Departm	t Assurance nent

	APPLICAT	Page 4	4			
ESCC	Component Title:	Capacitors, Microwave, Silicon, MOS, Nake 101M, 201M, 400M and 401M	d Die base	ed on Types	Appl. N	0.
	Executive Member:	CNES	Date:	26/01/2021	286F	
ANNEX 1: LIST OF TESTS DONE TO SUF	PPORT EXTENSION	OF QUALIFICATION				18
Tests conducted in compliance with:						-
 ESCC 5010 generic specificati Or PID-TFD 	on; Chart V (for ESC (for ESCC/QML	C/QPL parts); parts)				
Tests vehicle identification/description:						
101M104A100M	400M10	6A100M				
400M108C680M						
Detail Specification reference: 57	11/002					

Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
	Thermal Shock Test		ESCC 5010 Para. 9.5.2				Not required (naked die)
(0	Shock Test		MIL-STD-750 Test Method 2016				Not required (naked die)
group	Vibration Test		MIL-STD-750 Test Method 2056				Not required (naked die)
al Sub	Constant Acceleration		MIL-STD-750 Test Method 2006				Not required (naked die)
chanic	Seal Test		MIL-STD-750 Test Method 1071				Not required (naked die)
Environmental/Meo	Moisture Resistance		MIL-STD-750 Test Method 1021				Not required (naked die)
	Seal Test		MIL-STD-750 Test Method 1071				Not required (naked die)
	Electrical Measurements at Room Temp.		Table 2 of the Detail Specification				Not required (naked die)
	External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)
	Operating Life	\boxtimes	MIL-STD-750 Test Method 1026	2011	8	0	
durance Ibgroup	Electrical Measurements during Endur. Test	\boxtimes	Table 6 of the Detail Specification	2011	8	0	
лÑ	External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)

			APPLICATION FOR	EXTENSION O	F ESCC QU	ALIFICATION	I APPROVAL	Page 5
Ent.	ESCC	Co	Component title: Capacitors, Microwave, Silicon, MOS, Naked Die based on Types 101M, 201M, 400M and 401M					
		- E>	ecutive Member: CNES	8		Date: 2	26/01/2021	286F
Chart F4B	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if no Comments or	t performed. Rejection
p – nents	Electrical Measurements at Room Temp.		Table 2 of the Detail Specification				Not required (naked die)
Subgrou leasurem	Electrical Measurements at High & Low Temp's		Table 3 of the Detail Specification				Not required (naked die)
Electrical ectrical N	External Visual External Visual Inspection		ESCC Basic Specification No. 20500				Not required (naked die)	
	Special Testing		The Detail Specification				Not required (naked die)
jroup y ssts	Solderability Test		MIL-STD-750 Test Method 2026				Not required (naked die)
rical Subg Assembl ability Te	Permanence of Marking		ESCC Basic Specification No. 24800				Not required (naked die)
Electi Cap	Terminal Strength		MIL-STD-750 Test Method 2036				Not required (naked die)
lation	Internal Visual Inspection		ESCC Basic Specification No. 20400				Not required (naked die)
De- capsul sub gru	Bond Stregth		MIL-STD-750 Test Method 2037	2011	4	0		
e o	Die Shear	\boxtimes	MIL-STD-750 Test Method 2017	2011	4	0		

		APPLICATI	Page 7				
ES	SCC	Component title:	Capacitors, Mi 101M, 201M, 4	crowave, Silicon, MOS, 100M and 401M	Naked D	ie based on Types	Appl. No.
		Executive Member:	CNES		Date:	26/01/2021	286F
NOTE	S ON THE COMPL	ETION OF THE APP	LICATION FOR	M FOR ESCC QUALIFI	ICATION	EXTENSION APPROVAL	L
ENTRIES Form heading	shall indicate: - the - the entering date	title of the componen ; - the certificate num	t as given in its c ber and its sequ	letail specification or the ential suffix.	e name of	the series, family; - the Ex	ecutive Member;
Box 1	shall provide detai (the ESCC code is the detail specific identifying the con	ls given in the table; in s recommended to in ation as 'base on'; - nponent tested (e.g., v	particular there dicate the values under Test Veh voltage of coil for	shall be listed: - the vari s or values range, the to nicle enter either an ES r a relay); - under compo	iants or ra olerance, SCC code onent sim	ange of variants; - the rang the voltage, etc); the des e or the specific characte illar enter a cross if releva	e of components ignation given in rristic capable of nt.
Box 2; 3 and 4	As per QPL entry;	otherwise, an explana	ation of the char	ges must be supplied.			
Box 5	Will show the ES reported were per	CC Generic and Deta formed. If the specifica	ail specifications ations are differe	, including issue number ant from those current of	er and re n the date	evision letter, current at the of the application, see B	ne time the tests ox 6.
Box 6	Will show the devi deviations this mu indicate also whet	ations from the Gene st be listed in Box 15. her the test data devia	ric and Detail S In case the refe ates or not from	pecifications listed in Bo renced specification in E such current documents	ox 5, in pa 3ox 5 hav s.	articular deviations from te e currently a different issu	esting. In case of e and/or revision
Box 7	Must reference the	e report(s) supplied in	support of the a	pplication.			
Box 8	Should provide the to the ESCC Exec	e details of procuremen utive under the terms	nt to the full ESC of the relevant (C System, documentatio Generic Specification. A	on of all o n approp	f which should already hav riate table has been drawn	e been delivered n in this box.
Box 9	If the PID evolved be provided togeth	after the Original Qua ner with the reasons fo	lification or after or the changes. I	the last Extension of Q Major changes shall be	ualificatio	on, adequate details of suc arked.	ch evolution shall
Box 10	Identify the currer arranged as close	nt PID issue status, c as possible to the rec	late and actual juired date of ex	date of verification. The tension.	e date of	verification of the currer	t PID should be
Box 11	This box can be of practices, procedu out in accordance	completed only after a ires, material, etc. use with the requirements	a physical visit t d in manufacturi s of ESCC Basic	o the plant to confirm th ng the components are Specification No. 2020	hat no ur as descri 0 and its	nexplained changes occur bed in the PID. This surve findings shall be recorded	red and that the y shall be carried
Box 12	Provide details o Nonconformance(satisfactory results	f, or reference to, a s) (NCCS) occurred d s.	ny Destructive uring the qualified	Physical Analysis (DP cation validity period, sta	PA) and ating if es	Failure Analysis reports stablished corrective actio	as well as any n have produced
Box 13	Enter only the na Coordinator.	me of the Executive	Member (i.e., C	NES, DLR, ESTEC, et	c.) and t	ne signature of the respo	nsible Executive
Box 14	To be used when the relevant Box. I	there is a need to exp Box 14 can be broken	oand any of the into 14a, 14b, e	boxes from 1 through 1 tc. if several boxes have	2. Identify e to be ex	/ box affected and referen kpanded.	ice the Box 14 in
Box 15	Fill in Table as rec	uested.					
Box 16	Any additional act by the ESCC Exec	ion deemed necessar cutive should be listed	y by the Execut herein or the re	ive Member to bring the ason(s) to accept the ne	e submitte oncompli	ed data to a standard likel ance.	y to be accepted
Box 17	All Executive Mana entry, letters to the	ager recommendation e manufacturer, etc. sl	s on the applicat nall be entered o	ion itself, special conditi clearly in Box 19, signed	ions or re I by the re	strictions, modifications of epresentative for ESA, and	the QPL or QML d dated.
Box 18	Fill in Table as rec	juested.					
Box 19	Confidential Detail	s of PID changes incl	uding those of a	confidential nature, sha	all be pro	vided.	
Box 20	State noncomplia shall be sequentia	nce with reference to Ily numbered. If releva	specification(s) ant state 'None'.	and paragraph(s). To s	simplify r	eference in Box 16 each	nonconformance
Box 21	Any additional act by the ESCC Exec	ion deemed necessar cutive should be listed	y by the Execut herein or the re	ive Member to bring the ason(s) to accept the ne	e submitte oncompli	ed data to a standard likel ance.	y to be accepted
Box 22	Additional Comme	ents.					